

Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/643,078	NAKAZAWA ET AL.
Examiner	Art Unit	
David Q. Nguyen	2617	

ISSUE CLASSIFICATION

ORIGINAL				CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)							
455	63.1	455	67.13								
INTERNATIONAL CLASSIFICATION		370	278								
H	0	4	B	1/10/							
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